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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/766,212	01/29/2004	Masaru Takaishi	AI 325	3347
75	90 06/30/2006		EXAMINER	
RABIN & BERDO, P.C.			TOLEDO, FERNANDO L	
	N.W., Suite 500			·
Washington, DC 20005			ART UNIT	PAPER NUMBER
			2823	

DATE MAILED: 06/30/2006

Please find below and/or attached an Office communication concerning this application or proceeding.

	Application No.	Applicant(s)	- $U$
	10/766,212	TAKAISHI, MASARU	
Office Action Summary	Examiner	Art Unit	
	Fernando L. Toledo	2823	
The MAILING DATE of this communication ap	opears on the cover sheet with the	correspondence addre	ss
A SHORTENED STATUTORY PERIOD FOR REPL WHICHEVER IS LONGER, FROM THE MAILING I  - Extensions of time may be available under the provisions of 37 CFR 1 after SIX (6) MONTHS from the mailing date of this communication.  - If NO period for reply is specified above, the maximum statutory period  - Failure to reply within the set or extended period for reply will, by statu Any reply received by the Office later than three months after the mailine earned patent term adjustment. See 37 CFR 1.704(b).	DATE OF THIS COMMUNICATION  .136(a). In no event, however, may a reply be to divide a reply and will expire SIX (6) MONTHS from the cause the application to become ABANDON	N. imely filed in the mailing date of this commi ED (35 U.S.C. § 133).	
Status			
1)⊠ Responsive to communication(s) filed on 14 and 2a)⊠ This action is FINAL.      3)□ Since this application is in condition for allowed closed in accordance with the practice under 1.	is action is non-final. ance except for formal matters, p		erits is
Disposition of Claims			
4) □ Claim(s) 1-7 and 9 is/are pending in the appli 4a) Of the above claim(s) is/are withdress 5) □ Claim(s) is/are allowed.  6) □ Claim(s) 1-7 and 9 is/are rejected.  7) □ Claim(s) is/are objected to.  8) □ Claim(s) are subject to restriction and/	awn from consideration.		
Application Papers			
9) The specification is objected to by the Examination The drawing(s) filed on is/are: a) acceptable and applicant may not request that any objection to the Replacement drawing sheet(s) including the correct The oath or declaration is objected to by the Examination is objected to by the Examination is objected.	ccepted or b) objected to by the e drawing(s) be held in abeyance. So ction is required if the drawing(s) is o	ee 37 CFR 1.85(a). bjected to. See 37 CFR 1	• •
Priority under 35 U.S.C. § 119			
12) Acknowledgment is made of a claim for foreig a) All b) Some * c) None of:  1. Certified copies of the priority documer 2. Certified copies of the priority documer 3. Copies of the certified copies of the pri application from the International Bures * See the attached detailed Office action for a list	nts have been received. nts have been received in Applica ority documents have been receiv au (PCT Rule 17.2(a)).	tion No ved in this National Sta	ge
Attachment(s)  1) Notice of References Cited (PTO-892)  2) Notice of Draftsperson's Patent Drawing Review (PTO-948)  3) Information Disclosure Statement(s) (PTO-1449 or PTO/SB/08)  Paper No(s)/Mail Date	4) Interview Summar Paper No(s)/Mail [ 3) 5) Notice of Informal 6) Other:		2)

### DETAILED ACTION

## Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- Claims 1 7 and 9 are rejected under 35 U.S.C. 102(b) as being anticipated by Hsu et al.
   (U. S. Patent 6,143,645 A).
- 3. In re claim 1, Hsu, in the U. S. Patent 6,143,645 A; figures 1-3 and related text, discloses forming a silicon-containing thin film 500 in a region having a predetermined area including the inner surface of the contact hole on the surface of the semiconductor substrate; forming an aluminum-containing thin film 520 on the surface of the semiconductor substrate on which the silicon-containing thin film is formed; and heating the semiconductor substrate on which the aluminum-containing thin film is formed to such a temperature as to cause silicon to diffuse with respect to aluminum (Column 4, Lines 15-30 and Figure 3) and wherein the semiconductor substrate is provided with several cells each including the contact hole, and the ratio of the amount of silicon contained in the silicon-containing thin film formed in the region having the predetermined area per unit cell to the amount of aluminum supplied to a unit cell in the step of forming the aluminum thin film is not less than 0.1% and not more than 2% by atomic ratio (Figure 3).

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4. In re claim 2, Hsu discloses wherein the step of forming an aluminum-containing thin

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film and the step of heating the semiconductor substrate is carried out simultaneously (Column 4,

Lines 15 - 30).

5. In re claim 3, Hsu discloses wherein the step of heating the semiconductor substrate is

carried out after completing the step of forming an aluminum-containing thin film (Figure 3).

6. In re claim 4, Hsu discloses wherein the step of forming a silicon-containing thin film in

the region having the predetermined area includes the step of: forming a silicon-containing thin

film in a region larger than the predetermined area; and removing the silicon-containing thin film

so that the area of the silicon-containing thin film can become the abovementioned

predetermined area (Column 7, Lines 16 – 19).

7. In re claim 5, Hsu discloses wherein the step of removing the silicon-containing thin film

includes a step of removing the silicon-containing thin film using a mask having a predetermined

pattern (it is conventional in the art that to form a plug a mask must be used to avoid etching the

plug).

8. In re claim 6, Hsu discloses wherein the step of removing the silicon-containing thin film

includes a step of removing the silicon-containing thin film by etching (it is well-known in the

art and conventional to remove unwanted portions by etching).

9. In re claim 7, Hsu discloses wherein the predetermined area is not more than 99% of the

area of the aluminum-containing thin film formed in the step of forming the aluminum thin film

(Figure 2).

10. In re claim 9, Hsu discloses wherein the step of heating the semiconductor substrate

includes a step of heating the semiconductor substrate to 380°C - 570°C (Column 4, Lines 15 -

30).

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## Response to Arguments

11. Applicant's arguments filed 14 December 2005 have been fully considered but they are

not persuasive for the following reasons.

12. Applicant contests that the substrate is not heated in the reference of Hsu.

Examiner respectfully submits that Hsu discloses heating the substrate when the

aluminum alloy is being reflowed in cavity 202. Also Hsu discloses "filling was performed with

high pressure extrusion of aluminum alloy at a heater temperature of 450°C (column 4, lines 4 -

6).

13. Applicant contests that Hsu does not teach the claimed ratio.

Examiner respectfully submits that Hsu discloses such limitation in column 2, lines 1 -

20. Applicant argues that Hsu teaches that the aluminum alloy has several problems, however,

this is not teaching away and Hsu in fact teaches that it is well-known in the art to make contact

plugs of an aluminum alloy having at least 1% of silicon.

14. Applicant also contests that Hsu does not show multiple contact holes.

Examiner respectfully submits that Hsu teaches that CMOS technology has several

contact holes in column 1, lines 15 - 20.

15. This supplemental action supersedes the final action mailed on 6 March 2006.

#### Conclusion

16. THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time

policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Fernando L. Toledo whose telephone number is 571-272-1867. The examiner can normally be reached on Mon-Fri 12pm-7:30pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Matthew Smith can be reached on 571-272-1907. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

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Fernando L. Toledo Patent Examiner Art Unit 2823

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27 June 2006